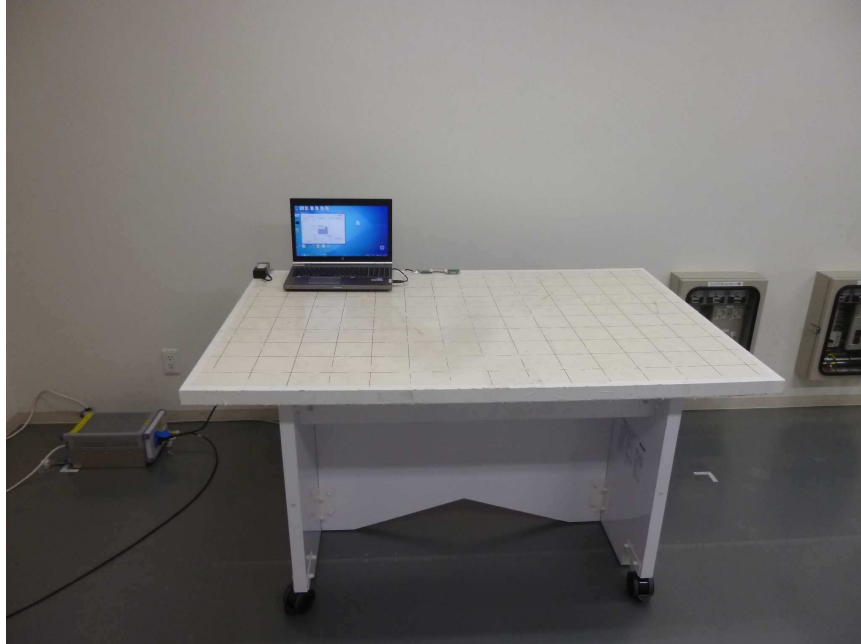

APPENDIX 3: Photographs of test setup

Conducted emission



(Front)



(Rear)

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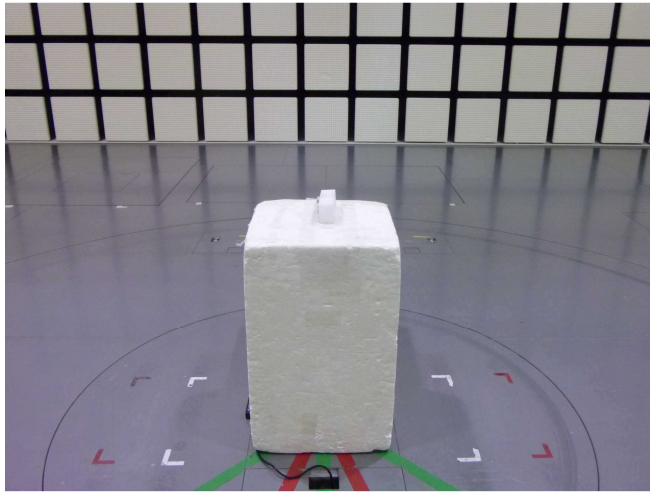
Shonan EMC Lab.

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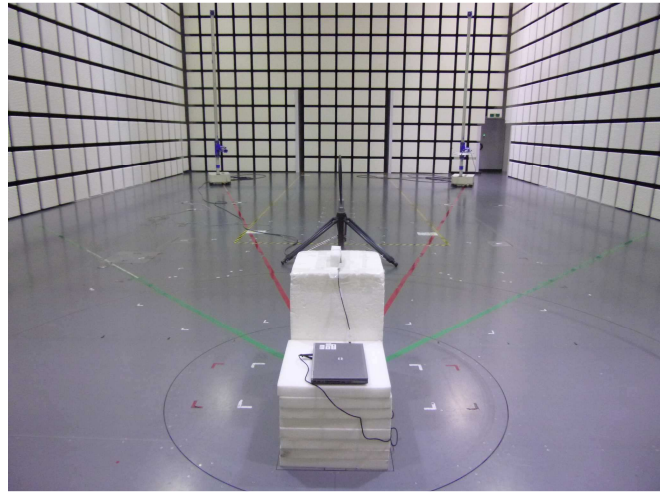
Telephone : +81 463 50 6400

Facsimile : +81 463 50 6401

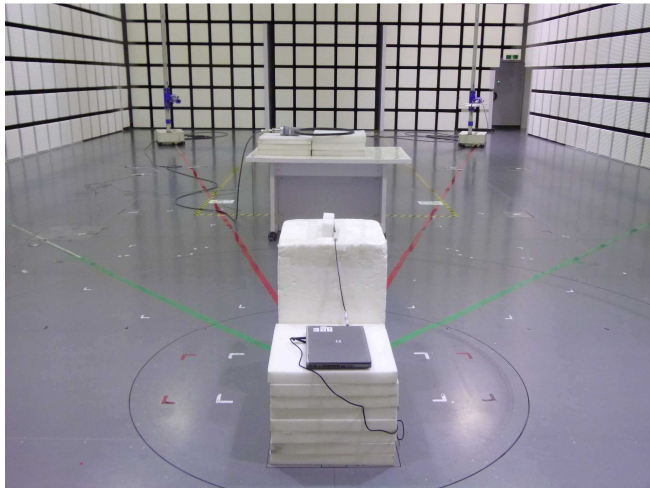
Radiated emission



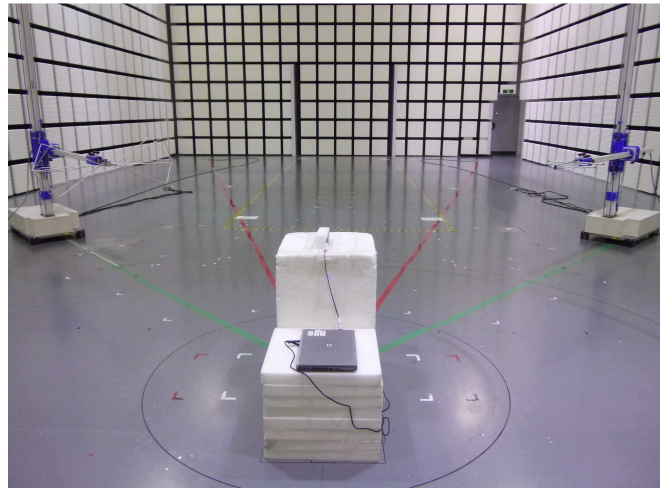
(Front)



(Rear, below 30 MHz, vertical)



(Rear, below 30 MHz, horizontal)



(Rear, above 30 MHz)

UL Japan, Inc.

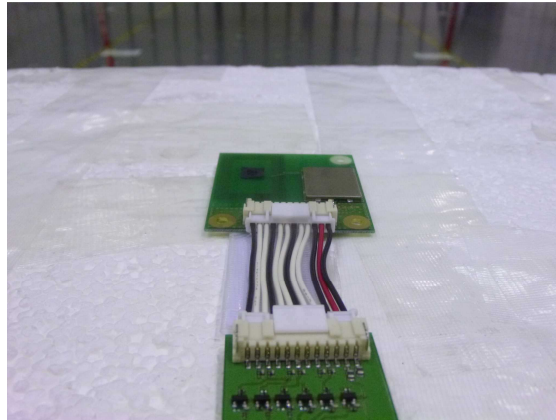
Shonan EMC Lab.

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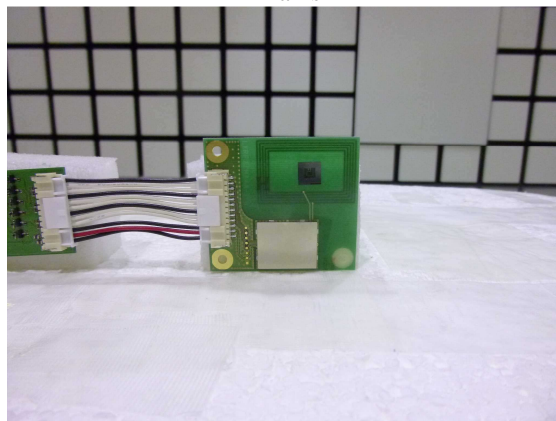
Telephone : +81 463 50 6400

Facsimile : +81 463 50 6401

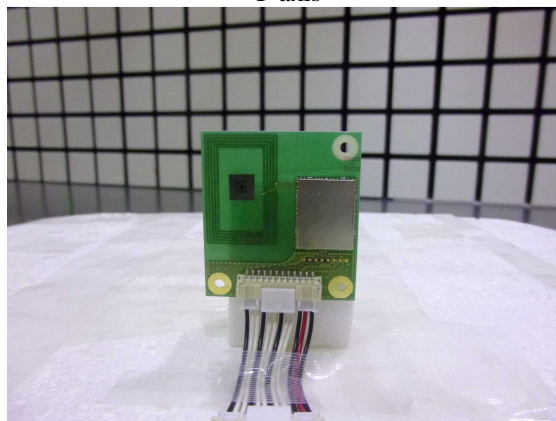
Pre-check of the worst position



X-axis



Y-axis



Z-axis

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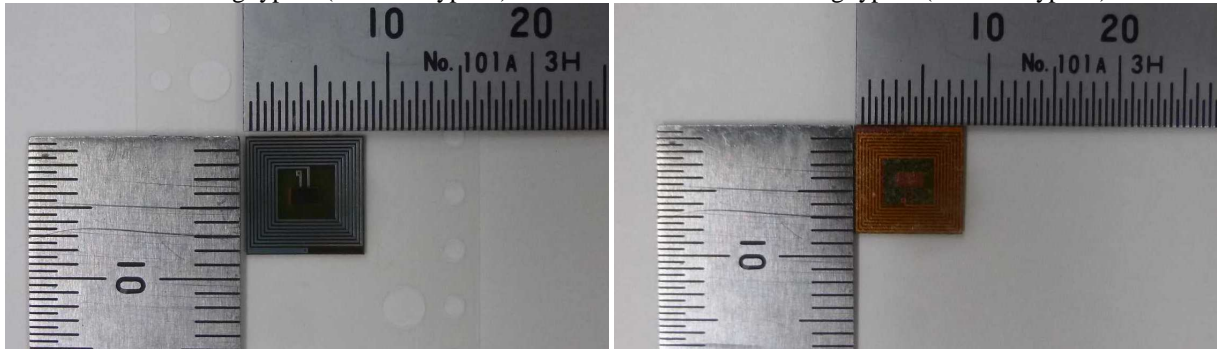
NFC Tags used as representatives

Front

Rear

NFC tag type 2 (for NFC type A)

NFC tag type 2 (for NFC type A)



END OF REPORT

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